

sampling switch change-over input portion start input portion

start input portion switch memory IC test start portion

memory portion sampling memory permissible value memory

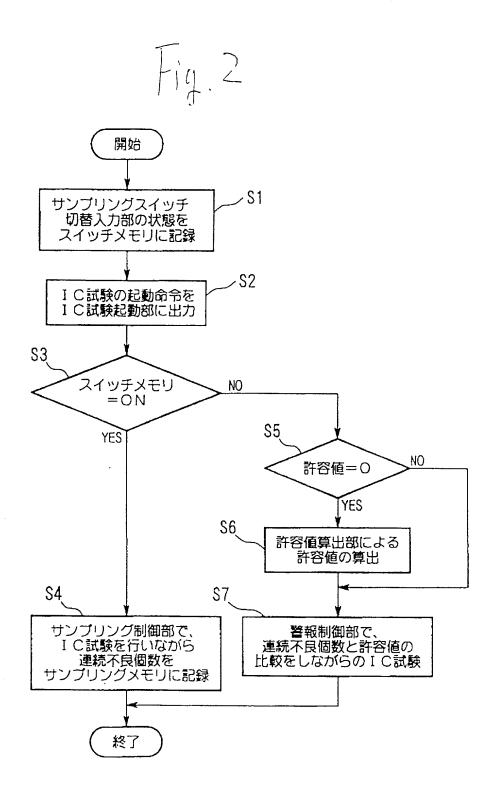
reasured value memory
sampling control portion
permissible value calculation portion
alarm control portion

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alarm display portion

IC test portion

14 18 28 20 202 203 203 27 38 34 44



S1 Record the state of the sampling switch change-over input portion in switch memory
S2 Supply start instruction of IC test to IC test start portion
S3 Is switch memory in ON state?
S4 Record number of continuous failures in sampling memory in sampling control portion while carrying out IC test.
S5 Is permissible value 0?
S6 Calculate permissible value in permissible value calculation portion
S7 Carry out IC test while comparing number of continuous failures with permissible value in alarm control portion

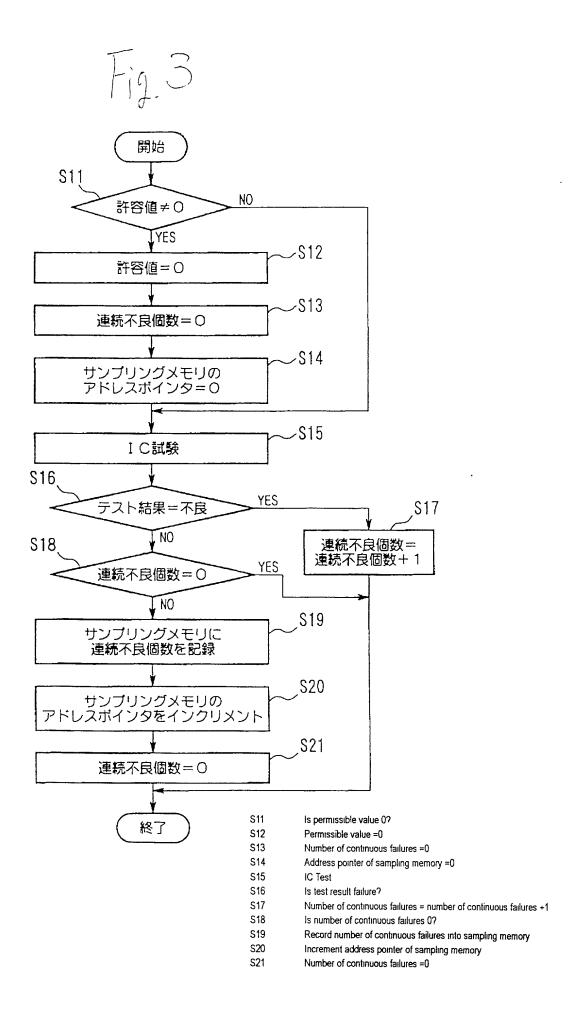
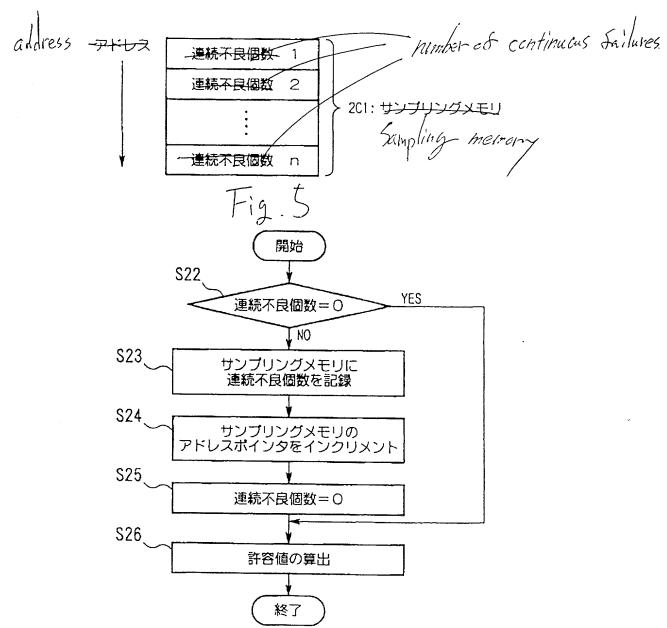
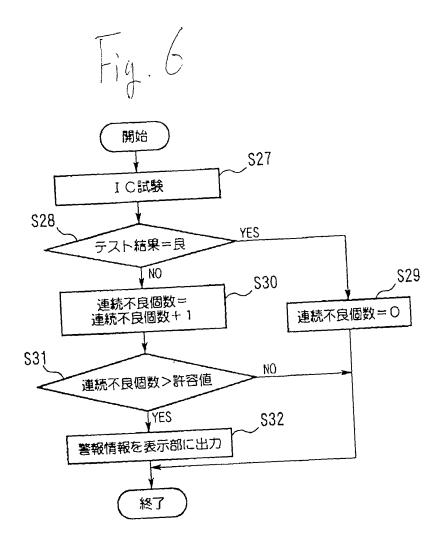


Fig. 4



S22 Is number of continuous failures 0?
S23 Record number of continuous failures into sampling memory.
S24 Increment address pointer of sampling memory.
S25 Number of continuous failures =0
S26 Calculate permissible value



S27	IC Test
S28	Is test result good?
S29	Number of continuous failures =0
S30	Number of continuous failures = number of continuous failures +1
S31	Is number of continuous failures larger than permissible value?
S32	Supply alarm information to display portion



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